

CT300 Meteor and CT300 Satellite

The CT 300 Meteor is a modular combinational testsystem for functional tests and in circuit tests including manufacturing defect analyzer. It will be used for prototype verification and series production. This modular testsystem is in 19" and suitable for testing small and large series semiconductor manufacturing with controlling various handling systems. The CT300 Meteor is available with 14 or 21 slots. The CT300 Satellite with 7 slots



Features:

- Function test 1GS/s analog
- ICT test pins: max. 1728 (14 Slots)
max. 2736 (21 Slots)
max. 720 (7 Slots) CT300 Satellite
- Function test 1GS/s analog
- Function test 300 MS/s digital
- PCB-CAD Import
- Parallel tests > 2500 Parts/s
- Powerful test operating system
- Test coverage analysis
- Grafical user interface
- Panel and multisite test
- Paperless repair station
- Automatic program generator
- Convenient Debugging
- Logging- and statistic functions
- Self test and self adjustment



Semiconductor-series production IC multisite test with CT300 Meteor parallel test of 32 chips